

IN THE CLAIMS:

1. (Currently Amended) A semiconductor device comprising:
 - a capacitance element one end of which is connected to a power supply, the capacitance element for detecting a voltage variation of the power supply;
 - a first comparator which has two input nodes having opposite polarity to each other, a first input node of the two input nodes for receiving and receives a reference voltage and a second input node of the two input nodes connected to an output of the other end of the capacitance element at their inputs to compare the respective voltage values to output a first output signal indicating a comparison result; and
 - a first resistor element which connects the ~~one side~~ first input node and the ~~other~~ side second input node of the first comparator; and
 - wherein the first comparator activates the output signal indicating the comparison result when the voltage difference between the inputted reference voltage and the inputted output of the other end of the capacitance element occurs.

2. (Currently Amended) A semiconductor device as defined in claim 1, wherein:
 - the first comparator is a hysteresis comparator which ~~activates outputs~~ outputs the first output signal indicating the first comparison result when the voltage difference between the inputted reference voltage and the ~~inputted~~ output of the other end of the capacitance element becomes larger than a predetermined hysteresis width.

3. (Currently Amended) A semiconductor device as defined in claim 1, ~~wherein~~ further comprising:

a second resistor element having a first end directly connected to said power supply; and
a third resistor elements resistor element having a first end connected to a second end of
the second resistor and having a second end directly connected to a connected in series between
the power supply voltage and the ground terminal to divide the power supply voltage;
a second comparator having two input nodes directly connected to the first end of the
third resistor element and the reference voltage terminal, respectively, and for outputting a
second output signal indicating a second comparison result and receives the voltage divided by
the second and the third resistor elements and the reference voltage at its inputs to compare
these; and
a logic OR circuit which ~~takes~~ performs a logic OR operation of the first output signal of
the first comparator and the second output signal of the second comparator.

4. (Currently Amended) A semiconductor device as defined in claim 3, ~~wherein~~ further comprising:

~~a reset portion which received circuit for receiving the an output signals signal of the first~~
~~comparator or the logic OR circuit at their inputs, and stops for halting the operation of the a~~
~~system including the semiconductor device when the output signal of the first comparator or the~~
~~output signal of the second comparator OR circuit is activated.~~

5. (Currently Amended) A semiconductor device as defined in claim 3, ~~wherein~~ further

comprising[[:]] a switching part which switches the for switching a value of the output of the other end of the capacitance element which is inputted to either of the input nodes of the first comparator to an arbitrary value.

6. (Currently Amended) Semiconductor A semiconductor device as defined in claim 5, wherein further comprising[[:]] a control section which operates the switching part at turning on the power of the semiconductor device.

7. (Currently Amended) A semiconductor device comprising:

a first capacitance element and a second capacitance elements element, one end of each of which is connected to a separate power supply, the first and second capacitance elements for detecting a voltage variation of each power supply;

a first comparator which has input nodes, the input nodes having opposite polarity to each other polarities and receiving a reference voltage and an output of the other end of the first capacitance element at their inputs to compare the respective voltage values to output a first signal indicating a first comparison result;

a second comparator which has two input nodes, the input nodes having opposite polarity to each other polarities and receiving a reference voltage and an output of the other end of the second capacitance element at their inputs to compare the respective voltage values to output a second signal indicating a second comparison result;

a first resistor element and a second resister elements resistor element each of which connects the one side input node and the other side input node of the first and the second

comparators, respectively;

a logic OR circuit ~~which takes for performing~~ a logic OR operation of the first output signal of the first comparator and the second output signal of the second comparator; ~~and~~ wherein the first and the second comparators output the first and second output signals, respectively, activate ~~the output signal indicating the comparison results when the a voltage difference is detected between inputted reference voltage and the inputted output of the other end of the respective first and second capacitance element occurs~~, and

the polarity of the input node which receives the output of the other end of the first capacitance element in the first comparator and the polarity of the input node which receives an output of the other end of the second capacitance element in the second comparator are opposite to each other.

8. (Currently Amended) A semiconductor device as defined as defined in claim 7 wherein:
the first comparator and the second comparator ~~respectively~~ are hysteresis comparators which ~~activate output the first and second output signal signals~~ indicating the respective comparison ~~result results~~ when ~~the a~~ voltage difference between the inputted reference voltage and the inputted output of the other end of the first and second capacitance element, ~~respectively~~, is larger than a predetermined hysteresis width.

9.-12. (Canceled)